Welcome to E-XFL.COM

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

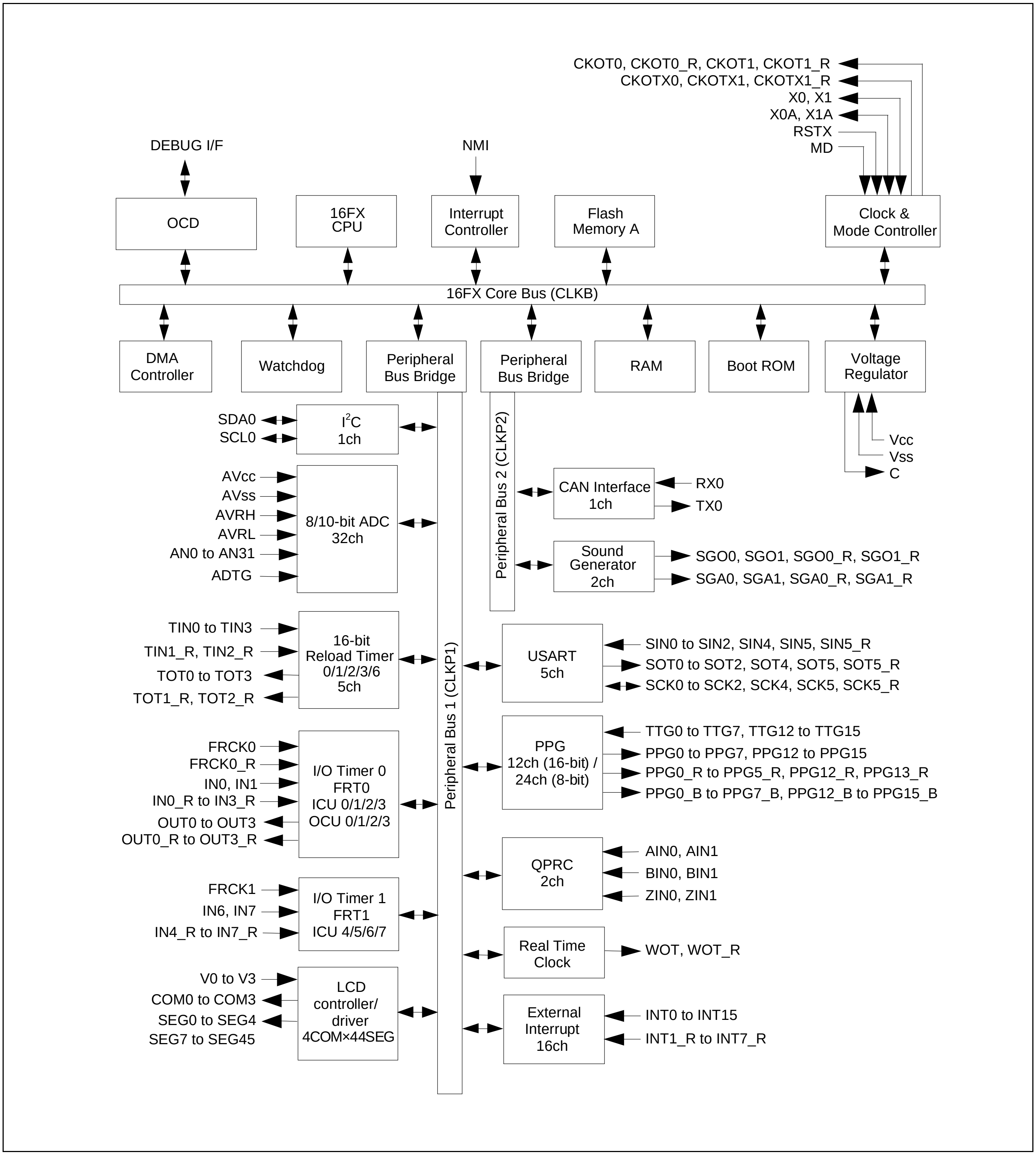
Details	
Product Status	Obsolete
Core Processor	F²MC-16FX
Core Size	16-Bit
Speed	32MHz
Connectivity	CANbus, I²C, LINbus, SCI, UART/USART
Peripherals	DMA, LCD, LVD, POR, PWM, WDT
Number of I/O	99
Program Memory Size	160KB (160K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 32x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	120-LQFP
Supplier Device Package	120-LQFP (16x16)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/mb96f6c5rbpmc-gse2

1. Product Lineup

Features		MB966C0	Remark
Product Type		Flash Memory Product	
Subclock		Subclock can be set by software	
Dual Operation Flash Memory	RAM	-	
128.5KB + 32KB	8KB	MB96F6C5R, MB96F6C5A	Product Options R: MCU with CAN A: MCU without CAN
256.5KB + 32KB	16KB	MB96F6C6R	
Package		LQFP-120 FPT-120P-M21	
DMA		4ch	
USART		5ch	LIN-USART 0 to 2/4/5
	with automatic LIN-Header transmission/reception	2ch	LIN-USART 0/1
	with 16 byte RX- and TX-FIFO		
I^2C		1ch	I^2C 0
8/10-bit A/D Converter		32ch	AN 0 to 31
	with Data Buffer	No	
	with Range Comparator	Yes	
	with Scan Disable	Yes	
	with ADC Pulse Detection	Yes	
16-bit Reload Timer (RLT)		5ch	RLT 0 to 3/6
16-bit Free-Running Timer (FRT)		2ch	FRT 0/1
16-bit Input Capture Unit (ICU)		8ch (5 channels for LIN-USART)	ICU 0 to 7 (ICU 0/1/4 to 6 for LIN-USART)
16-bit Output Compare Unit (OCU)		4ch	OCU 0 to 3
8/16-bit Programmable Pulse Generator (PPG)		12ch (16-bit) / 24ch (8-bit)	PPG 0 to 7/12 to 15
	with Timing point capture	Yes	
	with Start delay	Yes	
	with Ramp	No	
Quadrature Position/Revolution Counter (QPRC)		2ch	QPRC 0/1
CAN Interface		1ch	CAN 0 32 Message Buffers
External Interrupts (INT)		16ch	INT 0 to 15
Non-Maskable Interrupt (NMI)		1ch	
Sound Generator (SG)		2ch	SG 0/1
LCD Controller		4COM × 44SEG	COM 0 to 3 SEG 0 to 4/7 to 45
Real Time Clock (RTC)		1ch	
I/O Ports		97 (Dual clock mode) 99 (Single clock mode)	
Clock Calibration Unit (CAL)		1ch	
Clock Output Function		2ch	
Low Voltage Detection Function		Yes	Low voltage detection function can be disabled by software
Hardware Watchdog Timer		Yes	
On-chip RC-oscillator		Yes	
On-chip Debugger		Yes	

Note: All signals of the peripheral function in each product cannot be allocated by limiting the pins of package.
It is necessary to use the port relocate function of the general I/O port according to your function use.

2. Block Diagram



Pin name	Feature	Description
SINn	USART	USART n serial data input pin
SINn_R	USART	Relocated USART n serial data input pin
SOTn	USART	USART n serial data output pin
SOTn_R	USART	Relocated USART n serial data output pin
TINn	Reload Timer	Reload Timer n event input pin
TINn_R	Reload Timer	Relocated Reload Timer n event input pin
TOTn	Reload Timer	Reload Timer n output pin
TOTn_R	Reload Timer	Relocated Reload Timer n output pin
TTGn	PPG	Programmable Pulse Generator n trigger input pin
TXn	CAN	CAN interface n TX output pin
Vn	LCD	LCD voltage reference pin
Vcc	Supply	Power supply pin
Vss	Supply	Power supply pin
WOT	RTC	Real Time clock output pin
WOT_R	RTC	Relocated Real Time clock output pin
X0	Clock	Oscillator input pin
X0A	Clock	Subclock Oscillator input pin
X1	Clock	Oscillator output pin
X1A	Clock	Subclock Oscillator output pin
ZINn	QPRC	Quadrature Position/Revolution Counter Unit n input pin

Pin no.	I/O circuit type*	Pin name
77	J	P11_6 / SEG2 / FRCK0_R / ZIN1
78	J	P11_7 / SEG3 / IN0_R / AIN1
79	J	P12_0 / SEG4 / IN1_R / BIN1
80	H	P12_1 / TIN1_R / PPG0_B
81	H	P12_2 / TOT1_R / PPG1_B
82	J	P12_3 / SEG7 / OUT2_R
83	J	P12_4 / SEG8 / OUT3_R
84	J	P12_5 / SEG9 / TIN2_R / PPG2_B
85	J	P12_6 / SEG10 / TOT2_R / PPG3_B
86	J	P12_7 / SEG11 / INT1_R
87	J	P00_0 / SEG12 / INT3_R
88	J	P00_1 / SEG13 / INT4_R
89	J	P00_2 / SEG14 / INT5_R
90	Supply	Vcc
91	Supply	Vss
92	J	P00_3 / SEG15 / INT6_R
93	J	P00_4 / SEG16 / INT7_R
94	J	P00_5 / SEG17 / IN6 / TTG2 / TTG6
95	J	P00_6 / SEG18 / IN7 / TTG3 / TTG7
96	J	P00_7 / SEG19 / SGO0 / INT14
97	J	P01_0 / SEG20 / SGA0
98	J	P01_1 / SEG21 / CKOT1 / OUT0
99	J	P01_2 / SEG22 / CKOTX1 / OUT1 / INT15
100	J	P01_3 / SEG23 / PPG5
101	P	P01_4 / SEG24 / SIN4 / INT8
102	J	P01_5 / SEG25 / SOT4
103	P	P01_6 / SEG26 / SCK4 / TTG12
104	J	P01_7 / SEG27 / CKOTX1_R / INT9 / TTG13 / ZIN0
105	J	P02_0 / SEG28 / CKOT1_R / INT10 / TTG14 / AIN0
106	J	P02_1 / SEG29 / IN6_R / TTG15
107	J	P02_2 / SEG30 / IN7_R / CKOT0_R / INT12 / BIN0
108	J	P02_3 / SEG31 / SGO0_R / PPG12_B
109	J	P02_4 / SEG32 / SGA0_R / PPG13_B
110	P	P02_5 / SEG33 / OUT0_R / INT13 / SIN5_R
111	J	P02_6 / SEG34 / OUT1_R
112	J	P02_7 / SEG35 / PPG5_R
113	L	P03_0 / V0 / SEG36 / PPG4_B
114	L	P03_1 / V1 / SEG37 / PPG5_B
115	L	P03_2 / V2 / SEG38 / PPG14_B / SOT5_R

9. User ROM Memory Map for Flash Devices

CPU mode address	Flash memory mode address	MB96F6C5 Flash size 128.5KB + 32KB	MB96F6C6 Flash size 256.5KB + 32KB	
FF:FFFF$_H$ FF:0000$_H$	3F:FFFF$_H$ 3F:0000$_H$	SA39 - 64KB	SA39 - 64KB	Bank A of Flash A
FE:FFFF$_H$ FE:0000$_H$	3E:FFFF$_H$ 3E:0000$_H$	SA38 - 64KB	SA38 - 64KB	Bank A of Flash A
FD:FFFF$_H$ FD:0000$_H$	3D:FFFF$_H$ 3D:0000$_H$	Reserved	SA37 - 64KB	Bank A of Flash A
FC:FFFF$_H$ FC:0000$_H$	3C:FFFF$_H$ 3C:0000$_H$	Reserved	SA36 - 64KB	Bank A of Flash A
FB:FFFF$_H$ DF:A000$_H$		Reserved	Reserved	
DF:9FFF$_H$ DF:8000$_H$	1F:9FFF$_H$ 1F:8000$_H$	SA4 - 8KB	SA4 - 8KB	Bank B of Flash A
DF:7FFF$_H$ DF:6000$_H$	1F:7FFF$_H$ 1F:6000$_H$	SA3 - 8KB	SA3 - 8KB	Bank B of Flash A
DF:5FFF$_H$ DF:4000$_H$	1F:5FFF$_H$ 1F:4000$_H$	SA2 - 8KB	SA2 - 8KB	Bank B of Flash A
DF:3FFF$_H$ DF:2000$_H$	1F:3FFF$_H$ 1F:2000$_H$	SA1 - 8KB	SA1 - 8KB	Bank B of Flash A
DF:1FFF$_H$ DF:0000$_H$	1F:1FFF$_H$ 1F:0000$_H$	SAS - 512B*	SAS - 512B*	Bank A of Flash A
DE:FFFF$_H$ DE:0000$_H$		Reserved	Reserved	

*: Physical address area of SAS-512B is from DF:0000$_H$ to DF:01FF$_H$.
Others (from DF:0200$_H$ to DF:1FFF$_H$) is mirror area of SAS-512B.
Sector SAS contains the ROM configuration block RCBA at CPU address DF:0000$_H$ -DF:01FF$_H$.
SAS cannot be used for E^{2}PROM emulation.

11. Interrupt Vector Table

Vector number	Offset in vector table	Vector name	Cleared by DMA	Index in ICR to program	Description
0	$3FC_H$	CALLV0	No	-	CALLV instruction
1	$3F8_H$	CALLV1	No	-	CALLV instruction
2	$3F4_H$	CALLV2	No	-	CALLV instruction
3	$3F0_H$	CALLV3	No	-	CALLV instruction
4	$3EC_H$	CALLV4	No	-	CALLV instruction
5	$3E8_H$	CALLV5	No	-	CALLV instruction
6	$3E4_H$	CALLV6	No	-	CALLV instruction
7	$3E0_H$	CALLV7	No	-	CALLV instruction
8	$3DC_H$	RESET	No	-	Reset vector
9	$3D8_H$	INT9	No	-	INT9 instruction
10	$3D4_H$	EXCEPTION	No	-	Undefined instruction execution
11	$3D0_H$	NMI	No	-	Non-Maskable Interrupt
12	$3CC_H$	DLY	No	12	Delayed Interrupt
13	$3C8_H$	RC_TIMER	No	13	RC Clock Timer
14	$3C4_H$	MC_TIMER	No	14	Main Clock Timer
15	$3C0_H$	SC_TIMER	No	15	Sub Clock Timer
16	$3BC_H$	LVDI	No	16	Low Voltage Detector
17	$3B8_H$	EXTINT0	Yes	17	External Interrupt 0
18	$3B4_H$	EXTINT1	Yes	18	External Interrupt 1
19	$3B0_H$	EXTINT2	Yes	19	External Interrupt 2
20	$3AC_H$	EXTINT3	Yes	20	External Interrupt 3
21	$3A8_H$	EXTINT4	Yes	21	External Interrupt 4
22	$3A4_H$	EXTINT5	Yes	22	External Interrupt 5
23	$3A0_H$	EXTINT6	Yes	23	External Interrupt 6
24	$39C_H$	EXTINT7	Yes	24	External Interrupt 7
25	398_H	EXTINT8	Yes	25	External Interrupt 8
26	394_H	EXTINT9	Yes	26	External Interrupt 9
27	390_H	EXTINT10	Yes	27	External Interrupt 10
28	$38C_H$	EXTINT11	Yes	28	External Interrupt 11
29	388_H	EXTINT12	Yes	29	External Interrupt 12
30	384_H	EXTINT13	Yes	30	External Interrupt 13
31	380_H	EXTINT14	Yes	31	External Interrupt 14
32	$37C_H$	EXTINT15	Yes	32	External Interrupt 15
33	378_H	CAN0	No	33	CAN Controller 0
34	374_H	-	-	34	Reserved
35	370_H	-	-	35	Reserved
36	$36C_H$	-	-	36	Reserved
37	368_H	-	-	37	Reserved
38	364_H	PPG0	Yes	38	Programmable Pulse Generator 0
39	360_H	PPG1	Yes	39	Programmable Pulse Generator 1

12. Handling Precautions

Any semiconductor devices have inherently a certain rate of failure. The possibility of failure is greatly affected by the conditions in which they are used (circuit conditions, environmental conditions, etc.). This page describes precautions that must be observed to minimize the chance of failure and to obtain higher reliability from your Cypress semiconductor devices.

12.1 Precautions for Product Design

This section describes precautions when designing electronic equipment using semiconductor devices.

■Absolute Maximum Ratings

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of certain established limits, called absolute maximum ratings. Do not exceed these ratings.

■Recommended Operating Conditions

Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their sales representative beforehand.

■Processing and Protection of Pins

These precautions must be followed when handling the pins which connect semiconductor devices to power supply and input/output functions.

(1) Preventing Over-Voltage and Over-Current Conditions

Exposure to voltage or current levels in excess of maximum ratings at any pin is likely to cause deterioration within the device, and in extreme cases leads to permanent damage of the device. Try to prevent such overvoltage or over-current conditions at the design stage.

(2) Protection of Output Pins

Shorting of output pins to supply pins or other output pins, or connection to large capacitance can cause large current flows. Such conditions if present for extended periods of time can damage the device.
Therefore, avoid this type of connection.

(3) Handling of Unused Input Pins

Unconnected input pins with very high impedance levels can adversely affect stability of operation. Such pins should be connected through an appropriate resistance to a power supply pin or ground pin.

■Latch-up

Semiconductor devices are constructed by the formation of P-type and N-type areas on a substrate. When subjected to abnormally high voltages, internal parasitic PNPN junctions (called thyristor structures) may be formed, causing large current levels in excess of several hundred mA to flow continuously at the power supply pin. This condition is called latch-up.

CAUTION: The occurrence of latch-up not only causes loss of reliability in the semiconductor device, but can cause injury or damage from high heat, smoke or flame. To prevent this from happening, do the following:

(1) Be sure that voltages applied to pins do not exceed the absolute maximum ratings. This should include attention to abnormal noise, surge levels, etc.

(2) Be sure that abnormal current flows do not occur during the power-on sequence.

■Observance of Safety Regulations and Standards

Most countries in the world have established standards and regulations regarding safety, protection from electromagnetic interference, etc. Customers are requested to observe applicable regulations and standards in the design of products.

■Fail-Safe Design

Any semiconductor devices have inherently a certain rate of failure. You must protect against injury, damage or loss from such failures by incorporating safety design measures into your facility and equipment such as redundancy, fire protection, and prevention of over-current levels and other abnormal operating conditions.

■Static Electricity

Because semiconductor devices are particularly susceptible to damage by static electricity, you must take the following precautions:

(1) Maintain relative humidity in the working environment between 40% and 70%. Use of an apparatus for ion generation may be needed to remove electricity.

(2) Electrically ground all conveyors, solder vessels, soldering irons and peripheral equipment.

(3) Eliminate static body electricity by the use of rings or bracelets connected to ground through high resistance (on the level of 1 MΩ).
Wearing of conductive clothing and shoes, use of conductive floor mats and other measures to minimize shock loads is recommended.

(4) Ground all fixtures and instruments, or protect with anti-static measures.

(5) Avoid the use of styrofoam or other highly static-prone materials for storage of completed board assemblies.

12.3 Precautions for Use Environment

Reliability of semiconductor devices depends on ambient temperature and other conditions as described above.

For reliable performance, do the following:

(1) Humidity
Prolonged use in high humidity can lead to leakage in devices as well as printed circuit boards. If high humidity levels are anticipated, consider anti-humidity processing.

(2) Discharge of Static Electricity
When high-voltage charges exist close to semiconductor devices, discharges can cause abnormal operation. In such cases, use anti-static measures or processing to prevent discharges.

(3) Corrosive Gases, Dust, or Oil
Exposure to corrosive gases or contact with dust or oil may lead to chemical reactions that will adversely affect the device. If you use devices in such conditions, consider ways to prevent such exposure or to protect the devices.

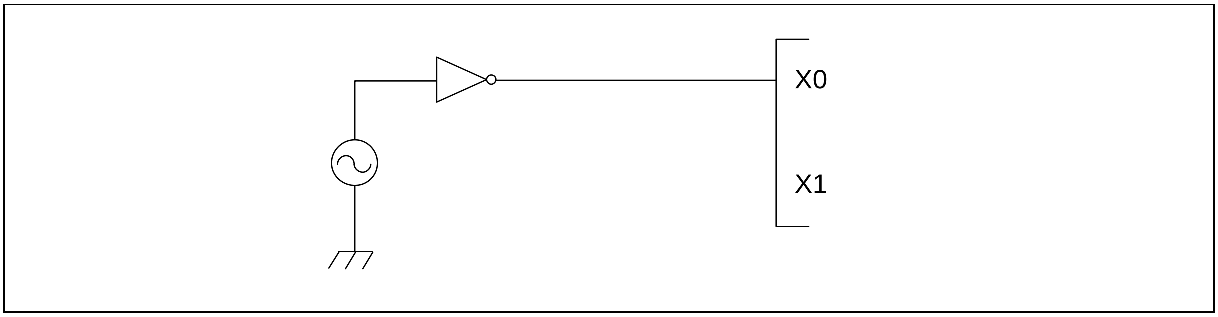
(4) Radiation, Including Cosmic Radiation
Most devices are not designed for environments involving exposure to radiation or cosmic radiation. Users should provide shielding as appropriate.

(5) Smoke, Flame
CAUTION: Plastic molded devices are flammable, and therefore should not be used near combustible substances. If devices begin to smoke or burn, there is danger of the release of toxic gases.

Customers considering the use of Cypress products in other special environmental conditions should consult with sales representatives.

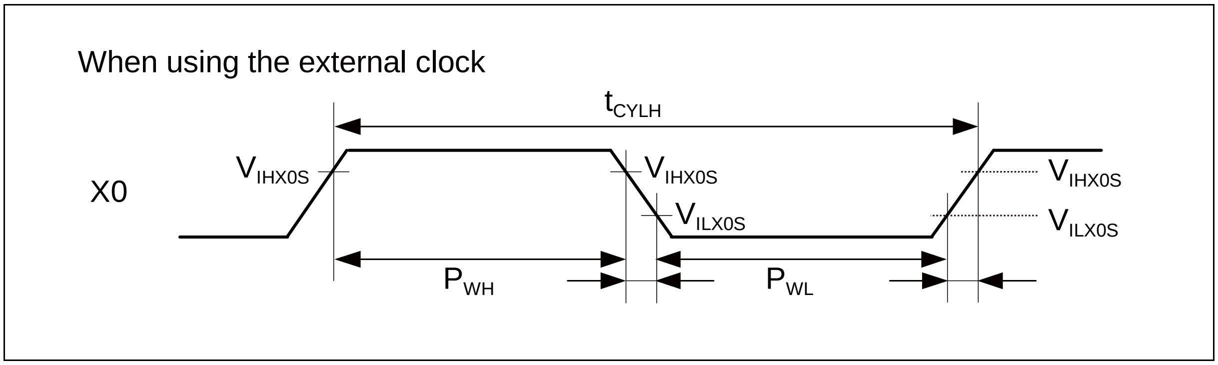
(1) Single phase external clock for Main oscillator

When using a single phase external clock for the Main oscillator, X0 pin must be driven and X1 pin left open.
And supply 1.8V power to the external clock.



- Use at DC voltage (current).
- The +B signal should always be applied a limiting resistance placed between the +B signal and the microcontroller.
- The value of the limiting resistance should be set so that when the +B signal is applied the input current to the microcontroller pin does not exceed rated values, either instantaneously or for prolonged periods.
- Note that when the microcontroller drive current is low, such as in the power saving modes, the +B input potential may pass through the protective diode and increase the potential at the V_{CC} pin, and this may affect other devices.
- Note that if a +B signal is input when the microcontroller power supply is off (not fixed at 0V), the power supply is provided from the pins, so that incomplete operation may result.
- Note that if the +B input is applied during power-on, the power supply is provided from the pins and the resulting supply voltage may not be sufficient to operate the Power reset.
- The DEBUG I/F pin has only a protective diode against V_{SS}. Hence it is only permitted to input a negative clamping current (4mA). For protection against positive input voltages, use an external clamping diode which limits the input voltage to maximum 6.0V.

Parameter	Symbol	Pin name	Conditions	Value			Unit	Remarks
				Min	Typ	Max		
Power supply current in Sleep modes[*1]	I_{CCSPLL}	Vcc	PLL Sleep mode with CLKS1/2 = CLKP1/2 = 32MHz (CLKRC and CLKSC stopped)	-	9.5	-	mA	T_A = +25°C
				-	-	15	mA	T_A = +105°C
				-	-	16.5	mA	T_A = +125°C
	$I_{CCSMAIN}$		Main Sleep mode with CLKS1/2 = CLKP1/2 = 4MHz, SMCR:LPMSS = 0 (CLKPLL, CLKRC and CLKSC stopped)	-	1.1	-	mA	T_A = +25°C
				-	-	4.7	mA	T_A = +105°C
				-	-	6.2	mA	T_A = +125°C
	I_{CCSRCH}		RC Sleep mode with CLKS1/2 = CLKP1/2 = CLKRC = 2MHz, SMCR:LPMSS = 0 (CLKMC, CLKPLL and CLKSC stopped)	-	0.6	-	mA	T_A = +25°C
				-	-	4.1	mA	T_A = +105°C
				-	-	5.6	mA	T_A = +125°C
	I_{CCSRCL}		RC Sleep mode with CLKS1/2 = CLKP1/2 = CLKRC = 100kHz (CLKMC, CLKPLL and CLKSC stopped)	-	0.07	-	mA	T_A = +25°C
				-	-	2.9	mA	T_A = +105°C
				-	-	4.4	mA	T_A = +125°C
	I_{CCSSUB}		Sub Sleep mode with CLKS1/2 = CLKP1/2 = 32kHz, (CLKMC, CLKPLL and CLKRC stopped)	-	0.04	-	mA	T_A = +25°C
				-	-	2.7	mA	T_A = +105°C
				-	-	4.2	mA	T_A = +125°C


When using the external clock
tCYLH
X0
VIHX0S
VIHX0S
VILX0S
VIHX0S
VILX0S
PWH
PWL

14.4.3 Built-in RC Oscillation Characteristics

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Value			Unit	Remarks
		Min	Typ	Max		
Clock frequency	f_{RC}	50	100	200	kHz	When using slow frequency of RC oscillator
		1	2	4	MHz	When using fast frequency of RC oscillator
RC clock stabilization time	t_{RCSTAB}	80	160	320	µs	When using slow frequency of RC oscillator (16 RC clock cycles)
		64	128	256	µs	When using fast frequency of RC oscillator (256 RC clock cycles)

14.4.4 Internal Clock Timing

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Value		Unit
		Min	Max	
Internal System clock frequency (CLKS1 and CLKS2)	f_{CLKS1}, f_{CLKS2}	-	54	MHz
Internal CPU clock frequency (CLKB), Internal peripheral clock frequency (CLKP1)	f_{CLKB}, f_{CLKP1}	-	32	MHz
Internal peripheral clock frequency (CLKP2)	f_{CLKP2}	-	32	MHz

14.4.8 USART Timing

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C, C_L=50pF)

Parameter	Symbol	Pin name	Conditions	4.5V ≤ V_{CC} < 5.5V		2.7V ≤ V_{CC} < 4.5V		Unit
				Min	Max	Min	Max	
Serial clock cycle time	t_{SCYC}	SCKn	Internal shift clock mode	$4t_{CLKP1}$	-	$4t_{CLKP1}$	-	ns
SCK ↓ → SOT delay time	t_{SLOVI}	SCKn, SOTn		- 20	+ 20	- 30	+ 30	ns
SOT → SCK ↑ delay time	t_{OVSHI}	SCKn, SOTn		$N \times t_{CLKP1}$ – 20*	-	$N \times t_{CLKP1}$ – 30*	-	ns
SIN → SCK ↑ setup time	t_{IVSHI}	SCKn, SINn		t_{CLKP1} + 45	-	t_{CLKP1} + 55	-	ns
SCK ↑ → SIN hold time	t_{SHIXI}	SCKn, SINn		0	-	0	-	ns
Serial clock "L" pulse width	t_{SLSH}	SCKn	External shift clock mode	t_{CLKP1} + 10	-	t_{CLKP1} + 10	-	ns
Serial clock "H" pulse width	t_{SHSL}	SCKn		t_{CLKP1} + 10	-	t_{CLKP1} + 10	-	ns
SCK ↓ → SOT delay time	t_{SLOVE}	SCKn, SOTn		-	$2t_{CLKP1}$ + 45	-	$2t_{CLKP1}$ + 55	ns
SIN → SCK ↑ setup time	t_{IVSHE}	SCKn, SINn		$t_{CLKP1}/2$ + 10	-	$t_{CLKP1}/2$ + 10	-	ns
SCK ↑ → SIN hold time	t_{SHIXE}	SCKn, SINn		t_{CLKP1} + 10	-	t_{CLKP1} + 10	-	ns
SCK fall time	t_F	SCKn		-	20	-	20	ns
SCK rise time	t_R	SCKn		-	20	-	20	ns

Notes:
- AC characteristic in CLK synchronized mode.
- CL is the load capacity value of pins when testing.
- Depending on the used machine clock frequency, the maximum possible baud rate can be limited by some parameters. These parameters are shown in "MB96600 series HARDWARE MANUAL".
- t_{CLKP1} indicates the peripheral clock 1 (CLKP1), Unit: ns
- These characteristics only guarantee the same relocate port number. For example, the combination of SCKn and SOTn_R is not guaranteed.

*: Parameter N depends on t_{SCYC} and can be calculated as follows:

- If $t_{SCYC} = 2 \times k \times t_{CLKP1}$, then N = k, where k is an integer > 2
- If $t_{SCYC} = (2 \times k + 1) \times t_{CLKP1}$, then N = k + 1, where k is an integer > 1

Examples:

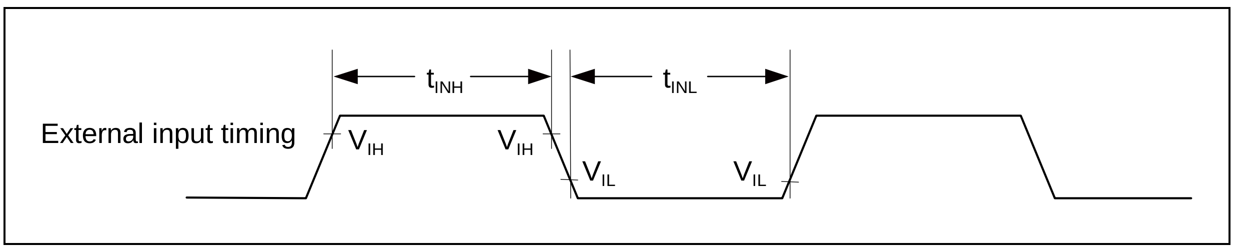
t_{SCYC}	N
$4 \times t_{CLKP1}$	2
$5 \times t_{CLKP1}$, $6 \times t_{CLKP1}$	3
$7 \times t_{CLKP1}$, $8 \times t_{CLKP1}$	4
...	...

14.4.9 *External Input Timing*

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Pin name	Value		Unit	Remarks
			Min	Max		
Input pulse width	t_{INH}, t_{INL}	Pnn_m	$2t_{CLKP1}$ +200 (t_{CLKP1}= $1/f_{CLKP1}$)*	-	ns	General Purpose I/O
		ADTG				A/D Converter trigger input
		TINn, TINn_R				Reload Timer
		TTGn				PPG trigger input
		FRCKn, FRCKn_R				Free-Running Timer input clock
		INn, INn_R				Input Capture
		AINn, BINn, ZINn				Quadrature Position/Revolution Counter
		INTn, INTn_R	200	-	ns	External Interrupt
		NMI				Non-Maskable Interrupt

*: t_{CLKP1} indicates the peripheral clock1 (CLKP1) cycle time except stop when in stop mode.



14.4.10 I²C Timing

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Conditions	Typical mode		High-speed mode*4		Unit
			Min	Max	Min	Max	
SCL clock frequency	f_{SCL}	C_L = 50pF, R = (Vp/I_{OL})*1	0	100	0	400	kHz
(Repeated) START condition hold time SDA↓ → SCL↓	t_{HDSTA}		4.0	-	0.6	-	µs
SCL clock "L" width	t_{LOW}		4.7	-	1.3	-	µs
SCL clock "H" width	t_{HIGH}		4.0	-	0.6	-	µs
(Repeated) START condition setup time SCL↑ → SDA↓	t_{SUSTA}		4.7	-	0.6	-	µs
Data hold time SCL↓ → SDA↓↑	t_{HDDAT}		0	3.45*2	0	0.9*3	µs
Data setup time SDA↓↑ → SCL↑	t_{SUDAT}		250	-	100	-	ns
STOP condition setup time SCL↑ → SDA↑	t_{SUSTO}		4.0	-	0.6	-	µs
Bus free time between "STOP condition" and "START condition"	t_{BUS}		4.7	-	1.3	-	µs
Pulse width of spikes which will be suppressed by input noise filter	t_{SP}	-	0	(1-1.5) × t_{CLKP1}*5	0	(1-1.5) × t_{CLKP1}*5	ns

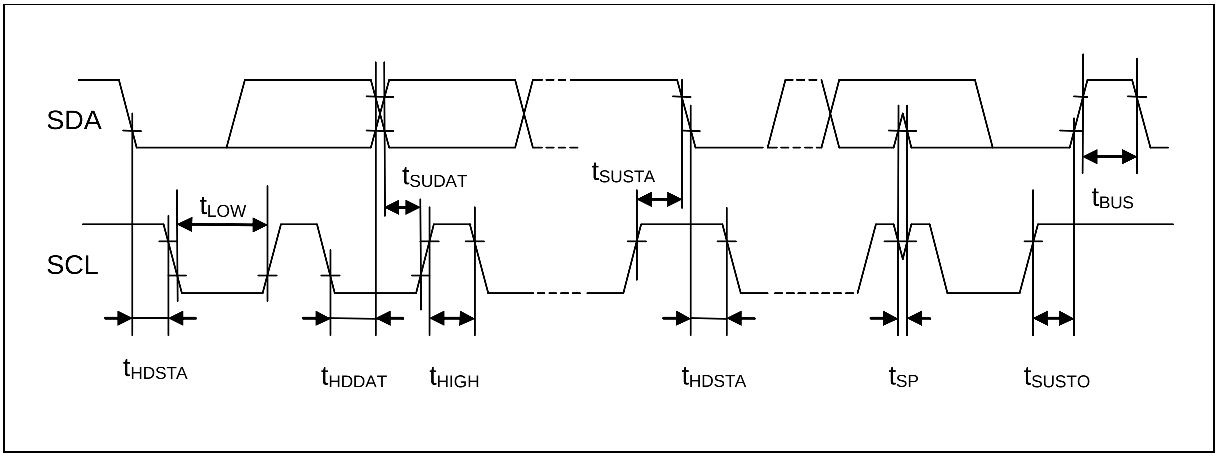
*1: R and C_L represent the pull-up resistance and load capacitance of the SCL and SDA lines, respectively.
Vp indicates the power supply voltage of the pull-up resistance and I_{OL} indicates V_{OL} guaranteed current.

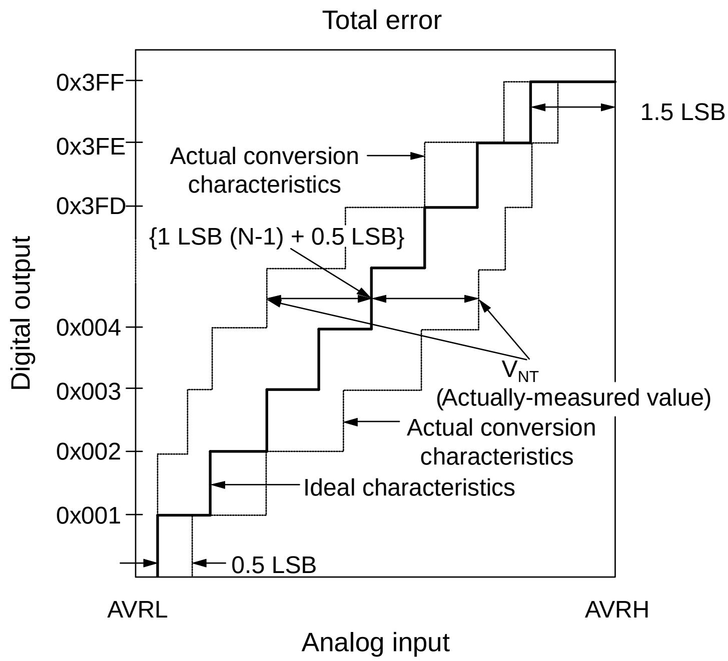
*2: The maximum t_{HDDAT} only has to be met if the device does not extend the "L" width (t_{LOW}) of the SCL signal.

*3: A high-speed mode I²C bus device can be used on a standard mode I²C bus system as long as the device satisfies the requirement of "t_{SUDAT} ≥ 250ns".

*4: For use at over 100kHz, set the peripheral clock1 (CLKP1) to at least 6MHz.

*5: t_{CLKP1} indicates the peripheral clock1 (CLKP1) cycle time.





$$1\text{LSB (Ideal value)} = \frac{\text{AVRH} - \text{AVRL}}{1024} \text{ [V]}$$

$$\text{Total error of digital output N} = \frac{V_{NT} - \{1\text{LSB} \times (\text{N} - 1) + 0.5\text{LSB}\}}{1\text{LSB}}$$

N : A/D converter digital output value.

V_{NT} : Voltage at which the digital output changes from 0x(N + 1) to 0xN.

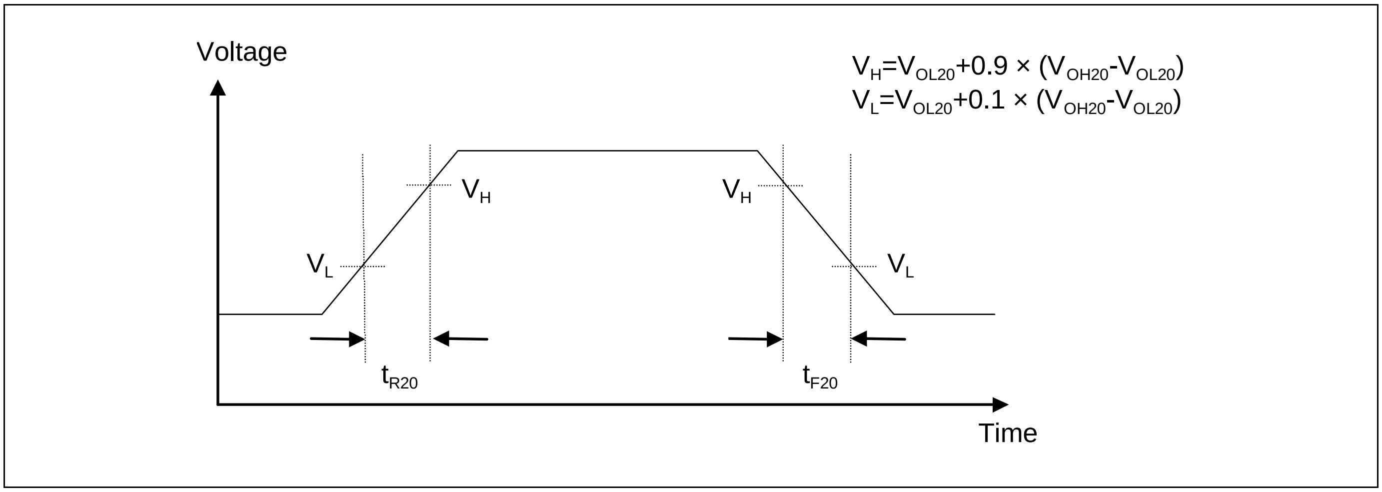
V_{OT} (Ideal value) = AVRL + 0.5LSB[V]

V_{FST} (Ideal value) = AVRH - 1.5LSB[V]

14.6 High Current Output Slew Rate

(V_{CC} = AV_{CC} = 2.7V to 5.5V, V_{SS} = AV_{SS} = 0V, T_A = - 40°C to + 125°C)

Parameter	Symbol	Pin name	Conditions	Value			Unit	Remarks
				Min	Typ	Max		
Output rise/fall time	t_{R20}, t_{F20}	P08_m, P09_m, P10_m	Outputs driving strength set to "20mA"	15	-	75	ns	C_L=85pF



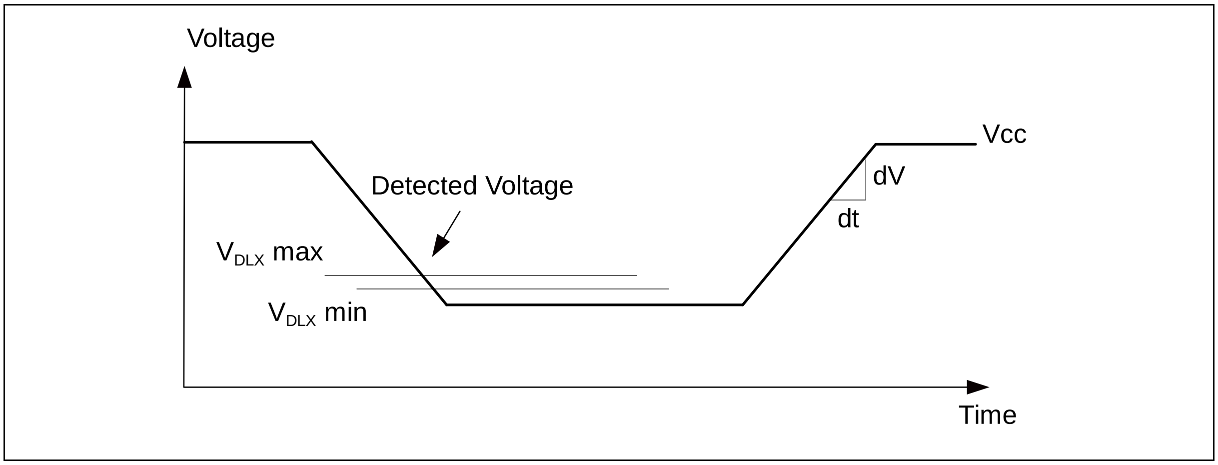
14.7 Low Voltage Detection Function Characteristics

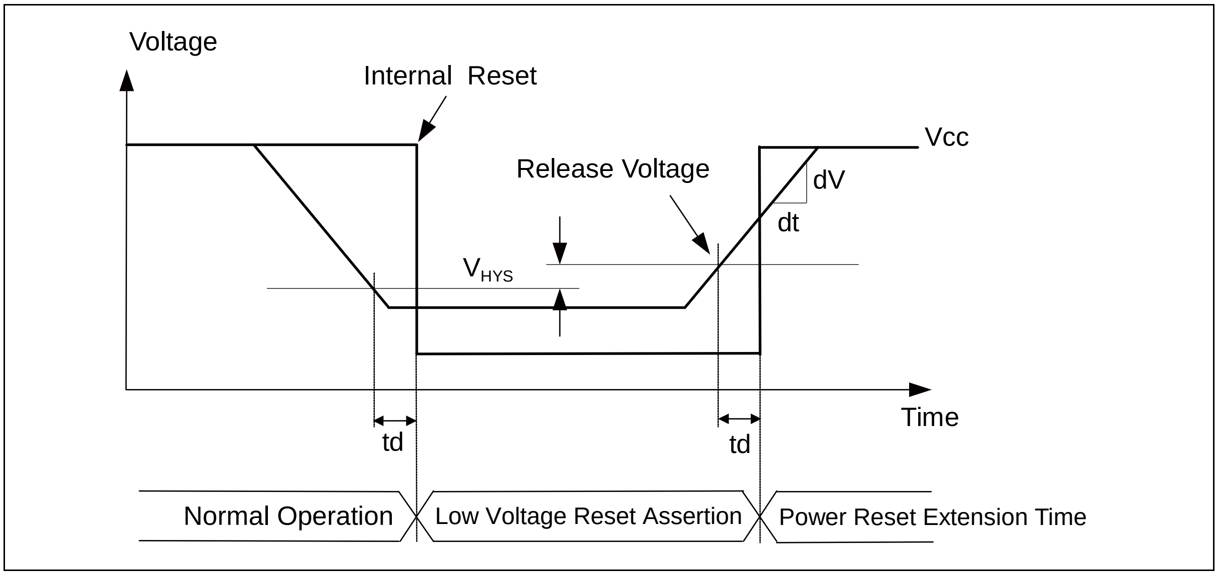
($V_{CC} = AV_{CC} = 2.7V$ to $5.5V$, $V_{SS} = AV_{SS} = 0V$, $T_A = -40°C$ to $+125°C$)

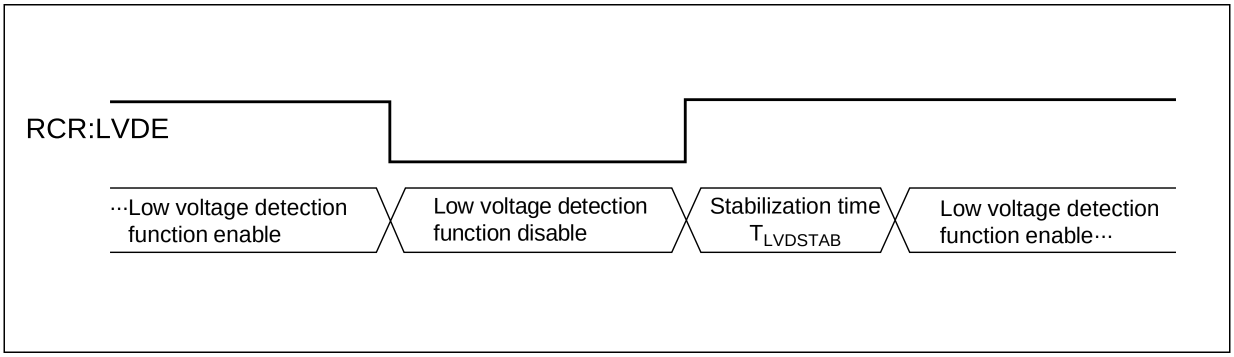
Parameter	Symbol	Conditions	Value			Unit
			Min	Typ	Max	
Detected voltage[*1]	V_{DL0}	CILCR:LVL = 0000_B	2.70	2.90	3.10	V
	V_{DL1}	CILCR:LVL = 0001_B	2.79	3.00	3.21	V
	V_{DL2}	CILCR:LVL = 0010_B	2.98	3.20	3.42	V
	V_{DL3}	CILCR:LVL = 0011_B	3.26	3.50	3.74	V
	V_{DL4}	CILCR:LVL = 0100_B	3.45	3.70	3.95	V
	V_{DL5}	CILCR:LVL = 0111_B	3.73	4.00	4.27	V
	V_{DL6}	CILCR:LVL = 1001_B	3.91	4.20	4.49	V
Power supply voltage change rate[*2]	dV/dt	-	- 0.004	-	+ 0.004	V/µs
Hysteresis width	V_{HYS}	CILCR:LVHYS=0	-	-	50	mV
		CILCR:LVHYS=1	80	100	120	mV
Stabilization time	$T_{LVDSTAB}$	-	-	-	75	µs
Detection delay time	t_d	-	-	-	30	µs

*1: If the power supply voltage fluctuates within the time less than the detection delay time (t_d), there is a possibility that the low voltage detection will occur or stop after the power supply voltage passes the detection range.

*2: In order to perform the low voltage detection at the detection voltage (V_{DLX}), be sure to suppress fluctuation of the power supply voltage within the limits of the change ration of power supply voltage.


Voltage
Vcc
dV
dt
Detected Voltage
V_{DLX} max
V_{DLX} min
Time


Voltage
Internal Reset
Vcc
Release Voltage
dV
dt
V_{HYS}
Time
td
td
Normal Operation
Low Voltage Reset Assertion
Power Reset Extension Time


RCR:LVDE
···Low voltage detection function enable
Low voltage detection function disable
Stabilization time $T_{LVDSTAB}$
Low voltage detection function enable···